

**Search Notes**

Application/Control No.

10/042,762

Examiner

Hanh Nguyen

Applicant(s)/Patent under  
Reexamination

LI ET AL.

Art Unit

2616

**SEARCHED**

Class	Subclass	Date	Examiner
375	240.11	3/28/2006	HN
	240.1		
	240.15		
	240.21		
	240.12		
	240.08		
	240		
370	235		
	229		
	230		
	236		
	238		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	3/28/2006	HN